

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T
		Country Code ³ -Number ⁴ -Kind Code ⁵ (<i>if known</i>)				
/V.W./	BA	JP-09-139543	05-27-1997	HITACHI LTD		v
/V.W./	BB	JP-11-074622	03-16-1999	TOKYO SHIBAURA ELECTRIC CO		v
/V.W./	BC	KR-1020010077971	08-20-2001	SAMSUNG ELECTRO- MECHANICS CO., LTD.		v
/V.W./	BD	JP-2003150315	05-23-2003	Lg Philips Lcd Co Ltd		v
/V.W./	BE	KR-1020040047132	06-05-2004	OPTRONIX INCORPORATED		v
/V.W./	BF	JP-983016	03-28-1997	NICHIA CHEM IND LTD		v

Examiner Signature	/Vernon Webb/	Date Considered	02/26/2010
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/Vernon Webb/